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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Detans	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	·
Total RAM Bits	36864
Number of I/O	68
Number of Gates	250000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-20°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a3pn250-z1vq100

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Microsemi

Global Resources in Low Power Flash Devices

I/О Туре	Beginning of I/O Name	Notes				
Single-Ended	GFAO/IOuxwByVz	Only one of the I/Os can be directly connected to a chip				
	GFA1/IOuxwByVz	global at a time.				
	GFA2/IOuxwByVz					
	GFBO/IOuxwByVz	Only one of the I/Os can be directly connected to a chip				
	GFB1/IOuxwByVz	global at a time.				
	GFB2/IOuxwByVz					
	GFC0/IOuxwByVz	Only one of the I/Os can be directly connected to a chip				
	GFC1/IOuxwByVz	global at a time.				
	GFC2/IOuxwByVz					
	GCAO/IOuxwByVz	Only one of the I/Os can be directly connected to a chip				
	GCA1/IOuxwByVz	global at a time.				
	GCA2/IOuxwByVz					
	GCBO/IOuxwByVz	Only one of the I/Os can be directly connected to a ch				
	GCB1/IOuxwByVz	global at a time.				
	GCB2/IOuxwByVz					
	GCC0/IOuxwByVz	Only one of the I/Os can be directly connected to a c				
	GCC1/IOuxwByVz	global at a time.				
	GCC2/IOuxwByVz					
Differential I/O Pairs	GFAO/IOuxwByVz	The output of the different pair will drive the chip global.				
	GFA1/IOuxwByVz					
	GFBO/IOuxwByVz	The output of the different pair will drive the chip global.				
	GFB1/IOuxwByVz					
	GFCO/IOuxwByVz	The output of the different pair will drive the chip global.				
	GFC1/IOuxwByVz					
	GCAO/IOuxwByVz	The output of the different pair will drive the chip global.				
	GCA1/IOuxwByVz					
	GCBO/IOuxwByVz	The output of the different pair will drive the chip global.				
	GCB1/IOuxwByVz					
	GCCO/IOuxwByVz	The output of the different pair will drive the chip global.				
	GCC1/IOuxwByVz					

Table 3-2 • Chip Global Pin Name

Note: Only one of the I/Os can be directly connected to a quadrant at a time.



Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs

Each CCC can implement up to three independent global buffers (with or without programmable delay) or a PLL function (programmable frequency division/multiplication, phase shift, and delays) with up to three global outputs. Unused global outputs of a PLL can be used to implement independent global buffers, up to a maximum of three global outputs for a given CCC.

CCC Programming

The CCC block is fully configurable, either via flash configuration bits set in the programming bitstream or through an asynchronous interface. This asynchronous dedicated shift register interface is dynamically accessible from inside the low power flash devices to permit parameter changes, such as PLL divide ratios and delays, during device operation.

To increase the versatility and flexibility of the clock conditioning system, the CCC configuration is determined either by the user during the design process, with configuration data being stored in flash memory as part of the device programming procedure, or by writing data into a dedicated shift register during normal device operation.

This latter mode allows the user to dynamically reconfigure the CCC without the need for core programming. The shift register is accessed through a simple serial interface. Refer to the "UJTAG Applications in Microsemi's Low Power Flash Devices" section on page 297 or the application note *Using Global Resources in Actel Fusion Devices*.

Global Resources

Low power flash and mixed signal devices provide three global routing networks (GLA, GLB, and GLC) for each of the CCC locations. There are potentially many I/O locations; each global I/O location can be chosen from only one of three possibilities. This is controlled by the multiplexer tree circuitry in each global network. Once the I/O location is selected, the user has the option to utilize the CCCs before the signals are connected to the global networks. The CCC in each location (up to six) has the same structure, so generating the CCC macros is always done with an identical software GUI. The CCCs in the corner locations drive the quadrant global networks, and the CCCs in the middle of the east and west chip sides drive the chip global networks. The quadrant global networks span only a quarter of the device, while the chip global networks span the entire device. For more details on global resources offered in low power flash devices, refer to the "Global Resources in Low Power Flash Devices" section on page 31.

A global buffer can be placed in any of the three global locations (CLKA-GLA, CLKB-GLB, or CLKC-GLC) of a given CCC. A PLL macro uses the CLKA CCC input to drive its reference clock. It uses the GLA and, optionally, the GLB and GLC global outputs to drive the global networks. A PLL macro can also drive the YB and YC regular core outputs. The GLB (or GLC) global output cannot be reused if the YB (or YC) output is used. Refer to the "PLL Macro Signal Descriptions" section on page 68 for more information.

Each global buffer, as well as the PLL reference clock, can be driven from one of the following:

- 3 dedicated single-ended I/Os using a hardwired connection
- 2 dedicated differential I/Os using a hardwired connection (not supported for IGLOO nano or ProASIC3 nano devices)
- The FPGA core

YB and YC are identical to GLB and GLC, respectively, with the exception of a higher selectable final output delay. The SmartGen PLL Wizard will configure these outputs according to user specifications and can enable these signals with or without the enabling of Global Output Clocks.

The above signals can be enabled in the following output groupings in both internal and external feedback configurations of the static PLL:

- One output GLA only
- Two outputs GLA + (GLB and/or YB)
- Three outputs GLA + (GLB and/or YB) + (GLC and/or YC)

PLL Macro Block Diagram

As illustrated, the PLL supports three distinct output frequencies from a given input clock. Two of these (GLB and GLC) can be routed to the B and C global network access, respectively, and/or routed to the device core (YB and YC).

There are five delay elements to support phase control on all five outputs (GLA, GLB, GLC, YB, and YC). There are delay elements in the feedback loop that can be used to advance the clock relative to the reference clock.

The PLL macro reference clock can be driven in the following ways:

- By an INBUF* macro to create a composite macro, where the I/O macro drives the global buffer (with programmable delay) using a hardwired connection. In this case, the I/O must be placed in one of the dedicated global I/O locations.
- 2. Directly from the FPGA core.
- 3. From an I/O that is routed through the FPGA regular routing fabric. In this case, users must instantiate a special macro, PLLINT, to differentiate from the hardwired I/O connection described earlier.

During power-up, the PLL outputs will toggle around the maximum frequency of the voltage-controlled oscillator (VCO) gear selected. Toggle frequencies can range from 40 MHz to 250 MHz. This will continue as long as the clock input (CLKA) is constant (HIGH or LOW). This can be prevented by LOW assertion of the POWERDOWN signal.

The visual PLL configuration in SmartGen, a component of the Libero SoC and Designer tools, will derive the necessary internal divider ratios based on the input frequency and desired output frequencies selected by the user.

Fusion CCC Locations

Fusion devices have six CCCs: one in each of the four corners and one each in the middle of the east and west sides of the device (Figure 4-17 and Figure 4-18). The device can have one integrated PLL in the middle of the west side of the device or two integrated PLLs in the middle of the east and west sides of the device (middle right and middle left).

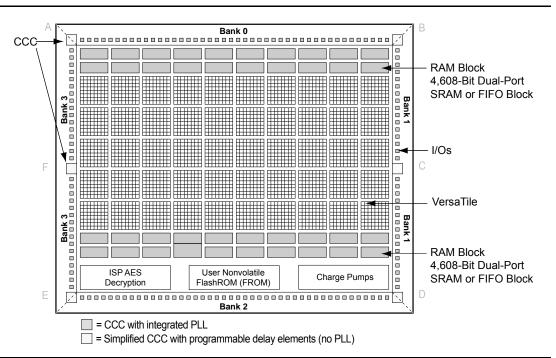


Figure 4-17 • CCC Locations in Fusion Family Devices (AFS090, AFS250, M1AFS250)

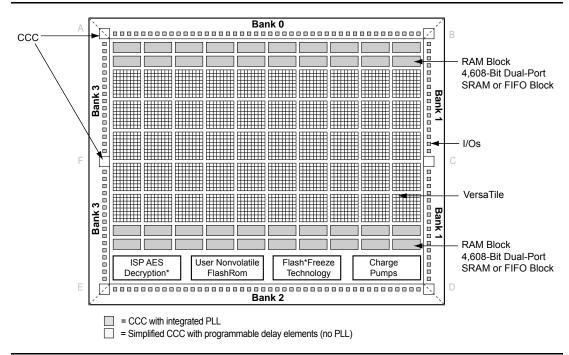


Figure 4-18 • CCC Locations in Fusion Family Devices (except AFS090, AFS250, M1AFS250)



Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs

Loading the Configuration Register

The most important part of CCC dynamic configuration is to load the shift register properly with the configuration bits. There are different ways to access and load the configuration shift register:

- JTAG interface
- Logic core
- Specific I/O tiles

JTAG Interface

The JTAG interface requires no additional I/O pins. The JTAG TAP controller is used to control the loading of the CCC configuration shift register.

Low power flash devices provide a user interface macro between the JTAG pins and the device core logic. This macro is called UJTAG. A user should instantiate the UJTAG macro in his design to access the configuration register ports via the JTAG pins.

For more information on CCC dynamic reconfiguration using UJTAG, refer to the "UJTAG Applications in Microsemi's Low Power Flash Devices" section on page 297.

Logic Core

If the logic core is employed, the user must design a module to provide the configuration data and control the shifting and updating of the CCC configuration shift register. In effect, this is a user-designed TAP controller, which requires additional chip resources.

Specific I/O Tiles

If specific I/O tiles are used for configuration, the user must provide the external equivalent of a TAP controller. This does not require additional core resources but does use pins.

Shifting the Configuration Data

To enter a new configuration, all 81 bits must shift in via SDIN. After all bits are shifted, SSHIFT must go LOW and SUPDATE HIGH to enable the new configuration. For simulation purposes, bits <71:73> and <77:80> are "don't care."

The SUPDATE signal must be LOW during any clock cycle where SSHIFT is active. After SUPDATE is asserted, it must go back to the LOW state until a new update is required.

PLL Configuration Bits Description

Table 4-8 • Configuration Bit Descriptions for the CCC Blocks

Config. Bits	Signal	Name	Description
<88:87>	GLMUXCFG [1:0] ¹		The configuration bits specify the input clocks to the NGMUX (refer to Table 4-17 on page 94). ²
86	OCDIVHALF ¹	,	When the PLL is bypassed, the 100 MHz RC oscillator can be divided by the divider factor in Table 4-18 on page 95.
85	OBDIVHALF ¹	,	When the PLL is bypassed, the 100 MHz RC oscillator can be divided by a 0.5 factor (refer to Table 4-18 on page 95).
84	OADIVHALF ¹		When the PLL is bypassed, the 100 MHz RC oscillator can be divided by certain 0.5 factor (refer to Table 4-16 on page 94).

Notes:

1. The <88:81> configuration bits are only for the Fusion dynamic CCC.

 This value depends on the input clock source, so Layout must complete before these bits can be set. After completing Layout in Designer, generate the "CCC_Configuration" report by choosing Tools > Report > CCC_Configuration. The report contains the appropriate settings for these bits.

Figure 4-31 • Static Timing Analysis Using SmartTime

Place-and-Route Stage Considerations

Several considerations must be noted to properly place the CCC macros for layout. For CCCs with clock inputs configured with the Hardwired I/O–Driven option:

- PLL macros must have the clock input pad coming from one of the GmA* locations.
- CLKDLY macros must have the clock input pad coming from one of the Global I/Os.

If a PLL with a Hardwired I/O input is used at a CCC location and a Hardwired I/O–Driven CLKDLY macro is used at the same CCC location, the clock input of the CLKDLY macro must be chosen from one of the GmB* or GmC* pin locations. If the PLL is not used or is an External I/O–Driven or Core Logic–Driven PLL, the clock input of the CLKDLY macro can be sourced from the GmA*, GmB*, or GmC* pin locations.

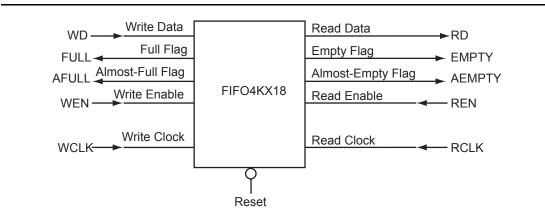
For CCCs with clock inputs configured with the External I/O–Driven option, the clock input pad can be assigned to any regular I/O location (IO******* pins). Note that since global I/O pins can also be used as regular I/Os, regardless of CCC function (CLKDLY or PLL), clock inputs can also be placed in any of these I/O locations.

By default, the Designer layout engine will place global nets in the design at one of the six chip globals. When the number of globals in the design is greater than six, the Designer layout engine will automatically assign additional globals to the quadrant global networks of the low power flash devices. If the user wishes to decide which global signals should be assigned to chip globals (six available) and which to the quadrant globals (three per quadrant for a total of 12 available), the assignment can be achieved with PinEditor, ChipPlanner, or by importing a placement constraint file. Layout will fail if the

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SRAM and FIFO Memories in Microsemi's Low Power Flash Devices

• Designer software will automatically facilitate falling-edge clocks by bubble-pushing the inversion to previous stages.





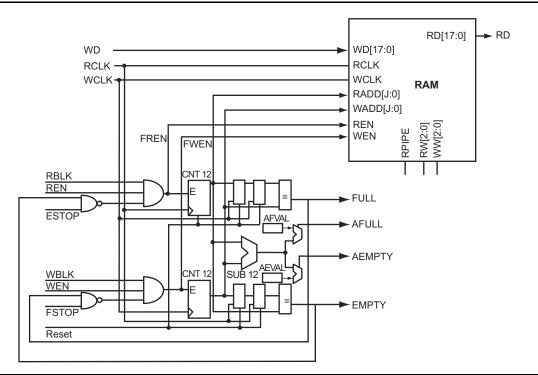


Figure 6-7 • RAM Block with Embedded FIFO Controller

The FIFOs maintain a separate read and write address. Whenever the difference between the write address and the read address is greater than or equal to the almost-full value (AFVAL), the Almost-Full flag is asserted. Similarly, the Almost-Empty flag is asserted whenever the difference between the write address and read address is less than or equal to the almost-empty value (AEVAL).

Due to synchronization between the read and write clocks, the Empty flag will deassert after the second read clock edge from the point that the write enable asserts. However, since the Empty flag is synchronized to the read clock, it will assert after the read clock reads the last data in the FIFO. Also, since the Full flag is dependent on the actual hardware configuration, it will assert when the actual physical implementation of the FIFO is full.

For example, when a user configures a 128×18 FIFO, the actual physical implementation will be a 256×18 FIFO element. Since the actual implementation is 256×18, the Full flag will not trigger until the

I/O Bank Architecture and CCC Naming Conventions

The nano products feature varying bank architectures which have been optimized to balance silicon area with I/O and clocking flexibility. The A standard naming scheme is used to illustrate the I/O Bank architecture and the CCCs associated with each architecture.

Name	Description
Bank x	Refers to the specific bank number within which an I/O resides
CCC	Clock Condition Circuit with simple clock delay operations as well as clock spine access
CCC-GL	Clock Condition Circuit with Global Locations for chip reach clocking. These CCCs support programmable delays but do not have an integrated PLL.
CCC-PLL	Clock Condition Circuit with integrated PLL and programmable delays
Chip Reach	Access to chip global lines
Quadrant Reach	Access to quadrant global lines

Table 7-16 • A Standard Naming Scheme

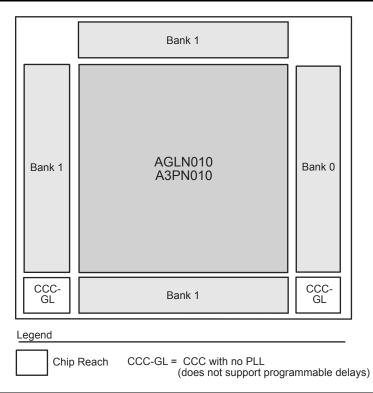


Figure 7-9 • I/O Bank Architecture of AGLN010 and A3PN010 Devices



Power-Up Behavior

Low power flash devices are power-up/-down friendly; i.e., no particular sequencing is required for power-up and power-down. This eliminates extra board components for power-up sequencing, such as a power-up sequencer.

During power-up, all I/Os are tristated, irrespective of I/O macro type (input buffers, output buffers, I/O buffers with weak pull-ups or weak pull-downs, etc.). Once I/Os become activated, they are set to the user-selected I/O macros. Refer to the "Power-Up/-Down Behavior of Low Power Flash Devices" section on page 307 for details.

Drive Strength

Low power flash devices have up to four programmable output drive strengths. The user can select the drive strength of a particular output in the I/O Attribute Editor or can instantiate a specialized I/O macro, such as OUTBUF_S_8 (slew = low, out_drive = 8 mA).

The maximum available drive strength is 8 mA per I/O. Though no I/O should be forced to source or sink more than 8 mA indefinitely, I/Os may handle a higher amount of current (refer to the device IBIS model for maximum source/sink current) during signal transition (AC current). Every device package has its own power dissipation limit; hence, power calculation must be performed accurately to determine how much current can be tolerated per I/O within that limit.

I/O Interfacing

Low power flash devices are 5 V–input– and 5 V–output–tolerant without adding any extra circuitry. Along with other low-voltage I/O macros, this 5 V tolerance makes these devices suitable for many types of board component interfacing.

Table 7-17 shows some high-level interfacing examples using low power flash devices.

		Clock	I/O							
Interface	Туре	Frequency	Туре	Signals In	Signals Out	Data I/O				
GM	Src Sync	125 MHz	LVTTL	8	8	125 Mbps				
ТВІ	Src Sync	125 MHz	LVTTL	10	10	125 Mbps				

Table 7-17 • nano High-Level Interface

Conclusion

IGLOO nano and ProASIC3 nano device support for multiple I/O standards minimizes board-level components and makes possible a wide variety of applications. The Microsemi Designer software, integrated with Libero SoC, presents a clear visual display of I/O assignments, allowing users to verify I/O and board-level design requirements before programming the device. The nano device I/O features and functionalities ensure board designers can produce low-cost and low power FPGA applications fulfilling the complexities of contemporary design needs.

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I/O Software Control in Low Power Flash Devices

List of Changes

The following table lists critical changes that were made in each revision of the document.

Date	Changes	Page
August 2012	The notes in Table 8-2 • Designer State (resulting from I/O attribute modification) were revised to clarify which device families support programmable input delay (SAR 39666).	187
June 2011	Figure 8-2 • SmartGen Catalog was updated (SAR 24310). Figure 8-3 • Expanded I/O Section and the step associated with it were deleted to reflect changes in the software.	188
	The following rule was added to the "VREF Rules for the Implementation of Voltage-Referenced I/O Standards" section:	199
	Only minibanks that contain input or bidirectional I/Os require a VREF. A VREF is not needed for minibanks composed of output or tristated I/Os (SAR 24310).	
July 2010	Notes were added where appropriate to point out that IGLOO nano and ProASIC3 nano devices do not support differential inputs (SAR 21449).	N/A
v1.4 (December 2008)	IGLOO nano and ProASIC3 nano devices were added to Table 8-1 • Flash-Based FPGAs.	186
	The notes for Table 8-2 • Designer State (resulting from I/O attribute modification) were revised to indicate that skew control and input delay do not apply to nano devices.	187
v1.3 (October 2008)	The "Flash FPGAs I/O Support" section was revised to include new families and make the information more concise.	186
v1.2 (June 2008)	The following changes were made to the family descriptions in Table 8-1 • Flash- Based FPGAs:	186
	ProASIC3L was updated to include 1.5 V.	
	The number of PLLs for ProASIC3E was changed from five to six.	
v1.1 (March 2008)	This document was previously part of the <i>I/O Structures in IGLOO and ProASIC3 Devices</i> document. The content was separated and made into a new document.	N/A
	Table 8-2 • Designer State (resulting from I/O attribute modification) was updated to include note 2 for IGLOO PLUS.	187

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DDR for Microsemi's Low Power Flash Devices

DDR Support in Flash-Based Devices

The flash FPGAs listed in Table 9-1 support the DDR feature and the functions described in this document.

Table 9-1 • Flash-Based FPGAs

Series	Family [*]	Description
IGLOO	IGLOO	Ultra-low power 1.2 V to 1.5 V FPGAs with Flash*Freeze technology
	IGLOOe	Higher density IGLOO FPGAs with six PLLs and additional I/O standards
	IGLOO nano	The industry's lowest-power, smallest-size solution
ProASIC3	ProASIC3	Low power, high-performance 1.5 V FPGAs
	ProASIC3E	Higher density ProASIC3 FPGAs with six PLLs and additional I/O standards
	ProASIC3 nano	Lowest-cost solution with enhanced I/O capabilities
	ProASIC3L	ProASIC3 FPGAs supporting 1.2 V to 1.5 V with Flash*Freeze technology
	RT ProASIC3	Radiation-tolerant RT3PE600L and RT3PE3000L
	Military ProASIC3/EL	Military temperature A3PE600L, A3P1000, and A3PE3000L
	Automotive ProASIC3	ProASIC3 FPGAs qualified for automotive applications
Fusion	Fusion	Mixed signal FPGA integrating ProASIC3 FPGA fabric, programmable analog block, support for ARM [®] Cortex [™] -M1 soft processors, and flash memory into a monolithic device

Note: *The device names link to the appropriate datasheet, including product brief, DC and switching characteristics, and packaging information.

IGLOO Terminology

In documentation, the terms IGLOO series and IGLOO devices refer to all of the IGLOO devices as listed in Table 9-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

ProASIC3 Terminology

In documentation, the terms ProASIC3 series and ProASIC3 devices refer to all of the ProASIC3 devices as listed in Table 9-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

To further understand the differences between the IGLOO and ProASIC3 devices, refer to the *Industry's Lowest Power FPGAs Portfolio*.



DDR for Microsemi's Low Power Flash Devices

```
DDR_OUT_0_inst : DDR_OUT
port map(DR => DataR, DF => DataF, CLK => CLK, CLR => CLR, Q => Q);
TRIBUFF_F_8U_0_inst : TRIBUFF_F_8U
port map(D => Q, E => TrienAux, PAD => PAD);
```

end DEF_ARCH;

DDR Bidirectional Buffer

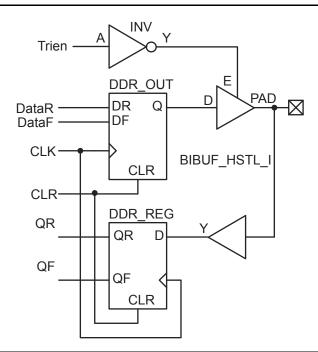


Figure 9-8 • DDR Bidirectional Buffer, LOW Output Enable (HSTL Class II)

Verilog

module DDR_BiDir_HSTL_I_LowEnb(DataR,DataF,CLR,CLK,Trien,QR,QF,PAD);

```
input DataR, DataF, CLR, CLK, Trien;
output QR, QF;
inout PAD;
wire TrienAux, D, Q;
INV Inv_Tri(.A(Trien), .Y(TrienAux));
DDR_OUT DDR_OUT_0_inst(.DR(DataR),.DF(DataF),.CLK(CLK),.CLR(CLR),.Q(Q));
DDR_REG DDR_REG_0_inst(.D(D),.CLK(CLK),.CLR(CLR),.QR(QR),.QF(QF));
BIBUF_HSTL_I BIBUF_HSTL_I_0_inst(.PAD(PAD),.D(Q),.E(TrienAux),.Y(D));
```

endmodule

Table 11-6 and Table 11-7 show all available options. If you want to implement custom levels, refer to the "Advanced Options" section on page 256 for information on each option and how to set it.

3. When done, click **Finish** to generate the Security Header programming file.

Security Option	FlashROM Only	FPGA Core Only	Both FlashROM and FPGA
No AES / no FlashLock	1	1	1
FlashLock only	1	1	1
AES and FlashLock	1	1	1

Note: \checkmark = options that may be used

Table 11-7 • All Fusion Header File Security Options

Security Option	FlashROM Only	FPGA Core Only	FB Core Only	All
No AES / No FlashLock	1	1	~	1
FlashLock	1	✓	1	1
AES and FlashLock	✓	✓	1	1

Generation of Programming Files with AES Encryption— Application 3

This section discusses how to generate design content programming files needed specifically at unsecured or remote locations to program devices with a Security Header (FlashLock Pass Key and AES key) already programmed ("Application 2: Nontrusted Environment—Unsecured Location" section on page 243 and "Application 3: Nontrusted Environment—Field Updates/Upgrades" section on page 244). In this case, the encrypted programming file must correspond to the AES key already programmed into the device. If AES encryption was previously selected to encrypt the FlashROM, FBs, and FPGA array, AES encryption must be set when generating the programming file for them. AES encryption can be applied to the FlashROM only, the FBs only, the FPGA array only, or all. The user must ensure both the FlashLock Pass Key and the AES key match those already programmed to the device(s), and all security settings must match what was previously programmed. Otherwise, the encryption and/or device unlocking will not be recognized when attempting to program the device with the programming file.

The generated programming file will be AES-encrypted.

In this scenario, generate the programming file as follows:

1. Deselect **Security settings** and select the portion of the device to be programmed (Figure 11-17 on page 254). Select **Programming previously secured device(s**). Click **Next**.

FlashROM and Programming Files

Each low power flash device has 1 kbit of on-chip, nonvolatile flash memory that can be accessed from the FPGA core. This nonvolatile FlashROM is arranged in eight pages of 128 bits (Figure 12-3). Each page can be programmed independently, with or without the 128-bit AES encryption. The FlashROM can only be programmed via the IEEE 1532 JTAG port and cannot be programmed from the FPGA core. In addition, during programming of the FlashROM, the FPGA core is powered down automatically by the on-chip programming control logic.

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Page	2																
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	0																

Figure 12-3 • FlashROM Architecture

When using FlashROM combined with AES, many subscription-based applications or device serialization applications are possible. The FROM configurator found in the Libero SoC Catalog supports easy management of the FlashROM contents, even over large numbers of devices. The FROM configurator can support FlashROM contents that contain the following:

- Static values
- Random numbers
- Values read from a file
- Independent updates of each page

In addition, auto-incrementing of fields is possible. In applications where the FlashROM content is different for each device, you have the option to generate a single STAPL file for all the devices or individual serialization files for each device. For more information on how to generate the FlashROM content for device serialization, refer to the "FlashROM in Microsemi's Low Power Flash Devices" section on page 117.

Libero SoC includes a unique tool to support the generation and management of FlashROM and FPGA programming files. This tool is called FlashPoint.

Depending on the applications, designers can use the FlashPoint software to generate a STAPL file with different contents. In each case, optional AES encryption and/or different security settings can be set.

In Designer, when you click the Programming File icon, FlashPoint launches, and you can generate STAPL file(s) with four different cases (Figure 12-4 on page 268). When the serialization feature is used during the configuration of FlashROM, you can generate a single STAPL file that will program all the devices or an individual STAPL file for each device.

The following cases present the FPGA core and FlashROM programming file combinations that can be used for different applications. In each case, you can set the optional security settings (FlashLock Pass Key and/or AES Key) depending on the application.

- A single STAPL file or multiple STAPL files with multiple FlashROM contents and the FPGA core content. A single STAPL file will be generated if the device serialization feature is not used. You can program the whole FlashROM or selectively program individual pages.
- 2. A single STAPL file for the FPGA core content

List of Changes

Date	Changes	Page		
August 2012	This chapter will now be published standalone as an application note in addition to being part of the IGLOO/ProASIC3/Fusion FPGA fabric user's guides (SAR 38769).	N/A		
	The "ISP Programming Header Information" section was revised to update the description of FP3-10PIN-ADAPTER-KIT in Table 12-3 • Programming Header Ordering Codes, clarifying that it is the adapter kit used for ProASIC ^{PLUS} based boards, and also for ProASIC3 based boards where a compact programming header is being used (SAR 36779).	269		
June 2011	The VPUMP programming mode voltage was corrected in Table 12-2 • Power Supplies. The correct value is 3.15 V to 3.45 V (SAR 30668).	263		
	The notes associated with Figure 12-5 • Programming Header (top view) and Figure 12-6 • Board Layout and Programming Header Top View were revised to make clear the fact that IGLOO nano V2 devices can be programmed at 1.2 V (SAR 30787).	269, 271		
	Figure 12-6 • Board Layout and Programming Header Top View was revised to include resistors tying TCK and TRST to GND. Microsemi recommends tying off TCK and TRST to GND if JTAG is not used (SAR 22921). RT ProASIC3 was added to the list of device families.	271		
	In the "ISP Programming Header Information" section, the kit for adapting ProASIC ^{PLUS} devices was changed from FP3-10PIN-ADAPTER-KIT to FP3-26PIN-ADAPTER-KIT (SAR 20878).	269		
July 2010	This chapter is no longer published separately with its own part number and version but is now part of several FPGA fabric user's guides.			
	References to FlashPro4 and FlashPro3X were added to this chapter, giving distinctions between them. References to SmartGen were deleted and replaced with Libero IDE Catalog.	N/A		
	The "ISP Architecture" section was revised to indicate that V2 devices can be programmed at 1.2 V VCC with FlashPro4.	261		
	SmartFusion was added to Table 12-1 • Flash-Based FPGAs Supporting ISP.	262		
	The "Programming Voltage (VPUMP) and VJTAG" section was revised and 1.2 V was added to Table 12-2 • Power Supplies.	263		
	The "Nonvolatile Memory (NVM) Programming Voltage" section is new.	263		
	Cortex-M3 was added to the "Cortex-M1 and Cortex-M3 Device Security" section.	265		
	In the "ISP Programming Header Information" section, the additional header adapter ordering number was changed from FP3-26PIN-ADAPTER to FP3-10PIN-ADAPTER-KIT, which contains 26-pin migration capability.	269		
	The description of NC was updated in Figure 12-5 • Programming Header (top view), Table 12-4 • Programming Header Pin Numbers and Description and Figure 12-6 • Board Layout and Programming Header Top View.	269, 270		
	The "Symptoms of a Signal Integrity Problem" section was revised to add that customers are expected to troubleshoot board-level signal integrity issues by measuring voltages and taking scope plots. "FlashPro4/3/3X allows TCK to be lowered from 6 MHz down to 1 MHz to allow you to address some signal integrity problems" formerly read, "from 24 MHz down to 1 MHz." "The Scan Chain command expects to see 0x2" was changed to 0x1.	271		

The following table lists critical changes that were made in each revision of the chapter.

2. VCC rises to 1.5 V before programming begins.

Figure 13-3 • Programming Algorithm

The oscilloscope plot in Figure 13-3 shows a wider time interval for the programming algorithm and includes the TDI and TMS signals from the FlashPro3. These signals carry the programming information that is programmed into the device and should only start toggling after the V_{CC} core voltage reaches 1.5 V. Again, TRST from FlashPro3 and the V_{CC} core voltage of the IGLOO device are labeled. As shown in Figure 13-3, TDI and TMS are floating initially, and the core voltage is 1.2 V. When a programming command on the FlashPro3 is executed, TRST is driven HIGH and TDI is momentarily driven to ground. In response to the HIGH TRST signal, the circuit responds and pulls the core voltage to 1.5 V. After 100 ms, TRST is briefly driven LOW by the FlashPro software. This is expected behavior that ensures the device JTAG state machine is in Reset prior to programming. TRST remains HIGH for the duration of the programming. It can be seen in Figure 13-3 that the VCC core voltage signal remains at 1.5 V for approximately 50 ms before information starts passing through on TDI and TMS. This confirms that the voltage switching circuit drives the VCC core supply voltage to 1.5 V prior to programming.

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Power-Up/-Down Behavior of Low Power Flash Devices

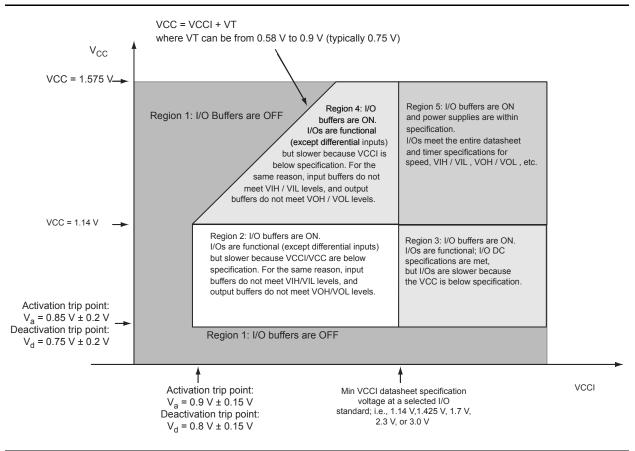


Figure 17-5 • I/O State as a Function of VCCI and VCC Voltage Levels for IGLOO V2, IGLOO nano V2, IGLOO PLUS V2, and ProASIC3L Devices Running at VCC = 1.2 V ± 0.06 V



Summary of Changes

Revision (month/year)	Chapter Affected	List of Changes (page number)
Revision 1 (continued)	"In-System Programming (ISP) of Microsemi's Low Power Flash Devices Using FlashPro4/3/3X" was revised.	273
	"Core Voltage Switching Circuit for IGLOO and ProASIC3L In-System Programming" was revised.	281
	"Boundary Scan in Low Power Flash Devices" was revised.	296
Revision 0 (April 2010)	The ProASIC3 nano Low Power Flash FPGAs Handbook was divided into two parts to create the ProASIC3 nano Datasheet ProASIC3 nano Device Family User's Guide.	

B – **Product Support**

Microsemi SoC Products Group backs its products with various support services, including Customer Service, Customer Technical Support Center, a website, electronic mail, and worldwide sales offices. This appendix contains information about contacting Microsemi SoC Products Group and using these support services.

Customer Service

Contact Customer Service for non-technical product support, such as product pricing, product upgrades, update information, order status, and authorization.

From North America, call 800.262.1060 From the rest of the world, call 650.318.4460 Fax, from anywhere in the world, 650.318.8044

Customer Technical Support Center

Microsemi SoC Products Group staffs its Customer Technical Support Center with highly skilled engineers who can help answer your hardware, software, and design questions about Microsemi SoC Products. The Customer Technical Support Center spends a great deal of time creating application notes, answers to common design cycle questions, documentation of known issues, and various FAQs. So, before you contact us, please visit our online resources. It is very likely we have already answered your questions.

Technical Support

Visit the Customer Support website (www.microsemi.com/soc/support/search/default.aspx) for more information and support. Many answers available on the searchable web resource include diagrams, illustrations, and links to other resources on the website.

Website

You can browse a variety of technical and non-technical information on the SoC home page, at www.microsemi.com/soc.

Contacting the Customer Technical Support Center

Highly skilled engineers staff the Technical Support Center. The Technical Support Center can be contacted by email or through the Microsemi SoC Products Group website.

Email

You can communicate your technical questions to our email address and receive answers back by email, fax, or phone. Also, if you have design problems, you can email your design files to receive assistance. We constantly monitor the email account throughout the day. When sending your request to us, please be sure to include your full name, company name, and your contact information for efficient processing of your request.

The technical support email address is soc_tech@microsemi.com.

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